

	Hi ts	Search Text	DBs
1	1	((MIM with capacitor) same DRAM) and ((photo or imageable or resist) with (layer\$4 or film\$3 or form\$4 or deposit\$4)) and (copper or Cu) and ((metal\$3 near oxide\$2) same photo\$3 same etch\$4) and ((tantalum or Ta) same (Cu or copper))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	1	((MIM with capacitor) same DRAM) and ((photo or imageable or resist) with (layer\$4 or film\$3 or form\$4 or deposit\$4)) and (copper or Cu) and (metal\$3 near \$3oxide\$2) and (photo same etch\$4) and ((tantalum or Ta) same (Cu or copper))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3	3	(MIM near2 capacitor) and DRAM and ((photo or imageable or resist) with (layer\$4 or film\$3 or form\$4 or deposit\$4)) and (copper or Cu) and (metal\$3 near2 \$3oxide\$2) and (photo\$4 same etch\$4) and ((tantalum or Ta) same (Cu or copper))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	2	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and (metal\$3 near2 \$3oxide\$2) and (photo\$4 same etch\$4 same pattern\$4) and ((tantalum or Ta) same (Cu or copper or Ta\$1Cu))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	2	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and ((metal\$3 or Ta or Ti or Si\$2) near2 \$3oxide\$2) and (photo\$4 same etch\$4) and (tantalum or Ta) and (Cu or copper or Ta\$1Cu) and (TaN same sputter\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
6	2	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and ((metal\$3 or Ta or Ti or Si\$2) near2 \$3oxide\$2) and (photo\$4 same etch\$4) and (tantalum or Ta) and (Cu or copper or Ta\$1Cu) and ((Ta\$2N or (tantalum near3 nitride)) same sputter\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Hi ts	Search Text	DBs
7	1	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and ((a\$3diamond or (black with diamond)) same (K or (absorption with coeff\$5) or low\$3K)) and (SiC or (silicon near3 carbide)) and (SiON or silicon\$3oxy\$2nitride)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
8	1	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and ((a\$3diamond or (black with diamond or diamond)) same (K or (absorption with coeff\$5) or low\$3K)) and (SiC or (silicon near3 carbide)) and (SiON or silicon\$3oxy\$2nitride)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
9	1	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and (a\$3diamond or (black with diamond) or diamond) and (K or (absorption with coeff\$5) or low\$3K) and (SiC or (silicon near3 carbide)) and (SiON or silicon\$3oxy\$2nitride)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	2	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and (a\$3diamond or (black with diamond) or diamond) and (K or (absorption with coeff\$5) or low\$3K or (low\$2k near3 dielectric))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
11	2	(MIM near2 capacitor) and DRAM and (photo or imageable or resist or photoresist) and (copper or Cu) and (metal\$3 near2 \$3oxide\$2) and (photo\$4 same etch\$4) and ((tantalum or Ta) same (Cu or copper or Ta\$1Cu)) and TaN	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB